On the Landau-Levich transition.

<u>G. Delon¹</u>, J. Snoeijer², B. Andreotti¹ & M. Fermigier¹. 1: Physique et Mécanique des Milieux Hétérogènes, ESPCI, Paris, France. 2: School of Mathematics, University of Bristol, University Walk, Bristol, UK

A solid surface can be coated by a thin film when the solid is withdrawn out of a bath of liquid. This dip coating process was first analyzed by Landau and Levich, who computed the thickness of the entrained film as a function of plate velocity. In the case of partial wetting, where the liquid does not naturally wet the plate, there is a threshold velocity below which the meniscus is steady and the solid remains dry. Liquid entrainment only occurs above this threshold value, and we investigate the dynamic wetting transition between from a stable meniscus to an entrained film. It has recently been predicted that a receding contact line becomes unstable when the capillary number exceeds a critical value $Ca_c^{\#}$ and that at this critical point perturbations of the contact line would relax with an infinite time.



figure : liquid film entrained by a vertical plate pulled out of a bath of silicone oil

In our experiments, however, liquid entrainment occurs at a capillary number Ca^* which is significantly lower than Ca_c . The critical behavior expected at Ca_c is thus avoided, and we observe that contact line perturbations decay with a finite relaxation time. The threshold velocity coincides precisely with the contact line velocity above the transition, and we attribute the early transition to the nucleation of a capillary ridge (see fig.) which moves ahead of the thin film. Hence, the characteristics of this ridge determine the threshold velocity for liquid entrainment. Observations are compared with a full-scale hydrodynamic model.

#: J. Eggers Phys. Fluids 17, 082106 (2005).

ref : J. H. Snoeijer, G. Delon, M. Fermigier et B. Andreotti, *Phys. Rev. Lett.* **96**, 174504 (2006), J. H. Snoeijer, B. Andreotti, G. Delon and M. Fermigier, *Journal of Fluid Mechanics*, Volume **579**, pp 63-83.